

N-channel 100V 13.9mΩ standard level MOSFET in I2PAK. Rev. 3 — 29 September 2011 Product data s

Product data sheet

#### **Product profile** 1.

#### **1.1 General description**

Standard level N-channel enhancement MOSFET in I2PAK package qualified to 175C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

#### 1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for high frequency applications due to fast switching characteristics

### **1.3 Applications**

- DC-to-DC converters
- Load switching

- Motor control
- Server power supplies

#### 1.4 Quick .

Table 1.	Quick reference da						
Symbol	Parameter	Conditions		Min	Тур	Max	Un
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	100	V
ID	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; see <u>Figure 1</u>	<u>[1]</u>	-	-	68	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	170	W
Tj	junction temperature			-55	-	175	°C
Static cha	aracteristics						
R <sub>DSon</sub> drain-source on-state resistance	on-state	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 100 °C; see <u>Figure 11</u>		-	-	25	mΩ
	resistance	$V_{GS}$ = 10 V; $I_D$ = 15 A; $T_j$ = 25 °C; see <u>Figure 12</u> ; see <u>Figure 11</u>	[2]	-	11	13.9	mΩ
Dynamic	characteristics						
Q <sub>GD</sub>	gate-drain charge	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \\ V_{DS} = 50 \text{ V}; \text{ see } \overline{Figure \ 14}; \\ \text{see } \overline{Figure \ 13} \end{array}$		-	17	-	nC



## **PSMN013-100ES**

#### N-channel 100V 13.9m $\Omega$ standard level MOSFET in I2PAK.

Table 1.         Quick reference datacontinued							
Symbol	Parameter	Conditions	I	Min	Тур	Max	Unit
Q <sub>G(tot)</sub>	total gate charge	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \\ V_{DS} = 50 \text{ V}; \text{ see } \overline{Figure \ 13}; \\ \text{see } \overline{Figure \ 14} \end{array}$	-	-	59	-	nC
Avalanch	e ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \text{ V};  \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \\ \text{I}_{D} = 68 \text{ A};  \text{V}_{sup} \leq 100 \text{ V}; \\ \text{unclamped};  \text{R}_{GS} = 50  \Omega \end{array}$	•	-	-	127	mJ

[1] Continuous current is limited by package.

[2] Measured 3 mm from package.

### 2. Pinning information

Table 2.	Pinning	g information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

SOT226 (I2PAK)

 $\begin{bmatrix} 1 & 2 & 1 \\ 1 & 2 & 3 \end{bmatrix}$ 

## 3. Ordering information

Table 3. Ordering in	nformation		
Type number	Package		
	Name	Description	Version
PSMN013-100ES	I2PAK	plastic single-ended package (I2PAK); TO-262	SOT226

N-channel 100V 13.9mΩ standard level MOSFET in I2PAK.

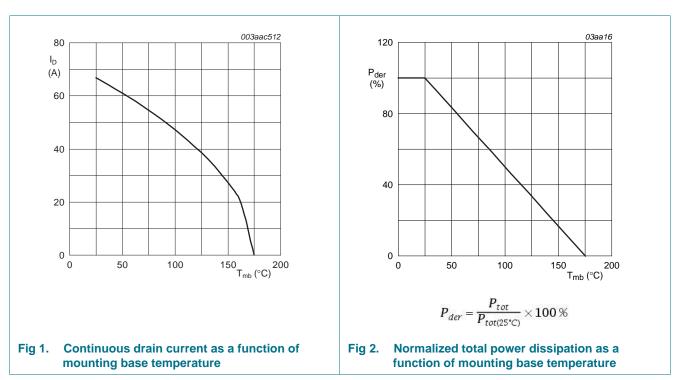
### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

		<b>03</b> ( <b>)</b>				
Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	100	V
V <sub>DGR</sub>	drain-gate voltage	T <sub>j</sub> ≤ 175 °C; T <sub>j</sub> ≥ 25 °C; R <sub>GS</sub> = 20 kΩ		-	100	V
V <sub>GS</sub>	gate-source voltage			-20	20	V
I <sub>D</sub>	drain current	$V_{GS}$ = 10 V; $T_{mb}$ = 100 °C; see <u>Figure 1</u>	<u>[1]</u>	-	47	А
		$V_{GS}$ = 10 V; $T_{mb}$ = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	68	А
I <sub>DM</sub>	peak drain current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	272	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	170	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
T <sub>sld(M)</sub>	peak soldering temperature			-	260	°C
Source-drai	in diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	<u>[1]</u>	-	68	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	272	А
Avalanche r	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 68 A; $V_{sup} \le$ 100 V; unclamped; $R_{GS}$ = 50 $\Omega$		-	127	mJ

[1] Continuous current is limited by package.

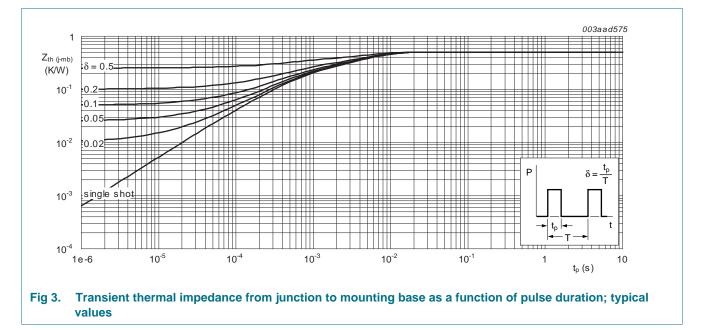


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N-channel 100V 13.9mΩ standard level MOSFET in I2PAK.

### 5. Thermal characteristics

Table J.	mermai enalacteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 3	-	0.5	0.9	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W



#### Table 5. Thermal characteristics

N-channel 100V 13.9mΩ standard level MOSFET in I2PAK.

### 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
-	racteristics	Conditions		19P	max	01111
	drain-source breakdown voltage	I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>i</sub> = -55 °C	90			V
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_i = 25 \text{ °C}$	100			V
Vaar	gate-source threshold voltage	$I_D = 0.25$ mA; $V_{DS} = V_{GS}$ ; $T_i = 175$ °C;	100			V
V <sub>GS(th)</sub>	gate-source intestion voltage	see Figure 9	1		-	v
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 10</u> ; see <u>Figure 9</u>	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see Figure 10	-	-	4.8	V
I <sub>DSS</sub>	drain leakage current	$V_{DS}$ = 100 V; $V_{GS}$ = 0 V; $T_j$ = 125 °C	-	-	100	μA
		$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.06	2	μA
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 20 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	10	100	nA
		V <sub>GS</sub> = -20 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	10	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 175 °C; see Figure 11	-	30	38.9	mΩ
		$V_{GS}$ = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 100 °C; see Figure 11	-	-	25	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C};$ see Figure 12; see Figure 11	<u>[1]</u> -	11	13.9	mΩ
R <sub>G</sub>	internal gate resistance (AC)	f = 1 MHz	-	1	-	Ω
Dynamic o	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 13; see Figure 14	-	59	-	nC
		$I_{\rm D} = 0 \text{ A}; V_{\rm DS} = 0 \text{ V}; V_{\rm GS} = 10 \text{ V}$	-	47.6	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 13; see Figure 14	-	13.8	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 14	-	9.2	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate-source charge		-	4.6	-	nC
Q <sub>GD</sub>	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 14; see Figure 13	-	17	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	$V_{DS} = 50 V$ ; see Figure 14; see Figure 13	-	4.4	-	V
C <sub>iss</sub>	input capacitance	V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 0 V; f = 1 MHz;	-	3195	-	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 15$	-	221	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	136	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 50 \text{ V}; \text{ R}_{L} = 2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	20.7	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 4.7 \ \Omega; \ T_j = 25 \ ^{\circ}C$	-	25	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	52.5	-	ns
t <sub>f</sub>	fall time			24	-	ns

## **PSMN013-100ES**

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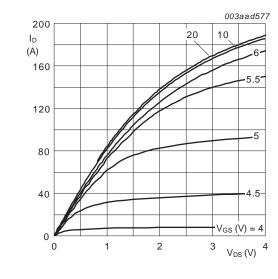
#### N-channel 100V 13.9mΩ standard level MOSFET in I2PAK.

Table 6. Characteristicsc	ontinued
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	ondracteristicscontanded					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-d	rain diode					
$V_{SD}$	source-drain voltage	I <sub>S</sub> = 15 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C; see <u>Figure 16</u>	-	0.8	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S} = 25 \text{ A}; \text{ dI}_{S}/\text{dt} = 100 \text{ A}/\mu\text{s};$	-	52	-	ns
Qr	recovered charge	$V_{GS} = 0 V; V_{DS} = 50 V$	-	109	-	nC

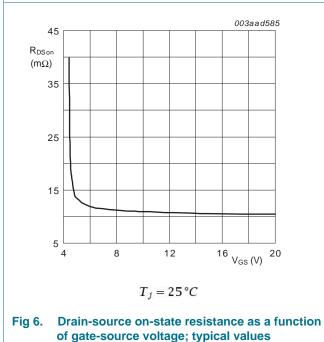
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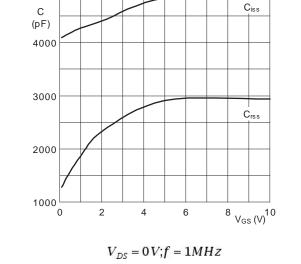
[1] Measured 3 mm from package.



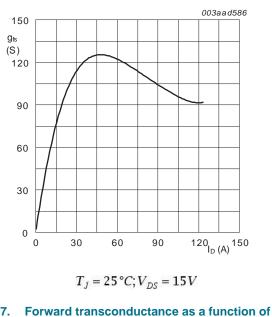
 $T_j = 25 \,^{\circ}C$ 







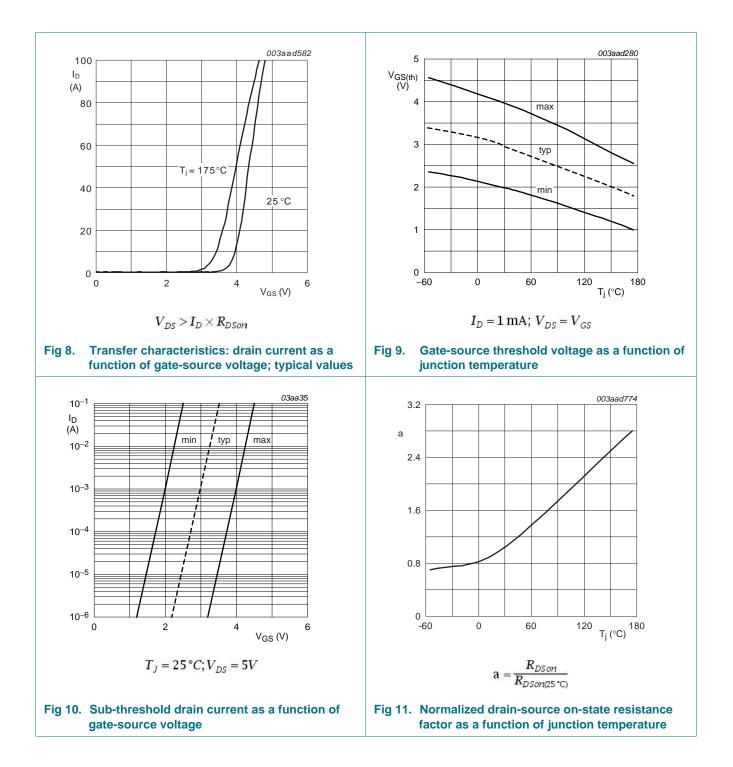






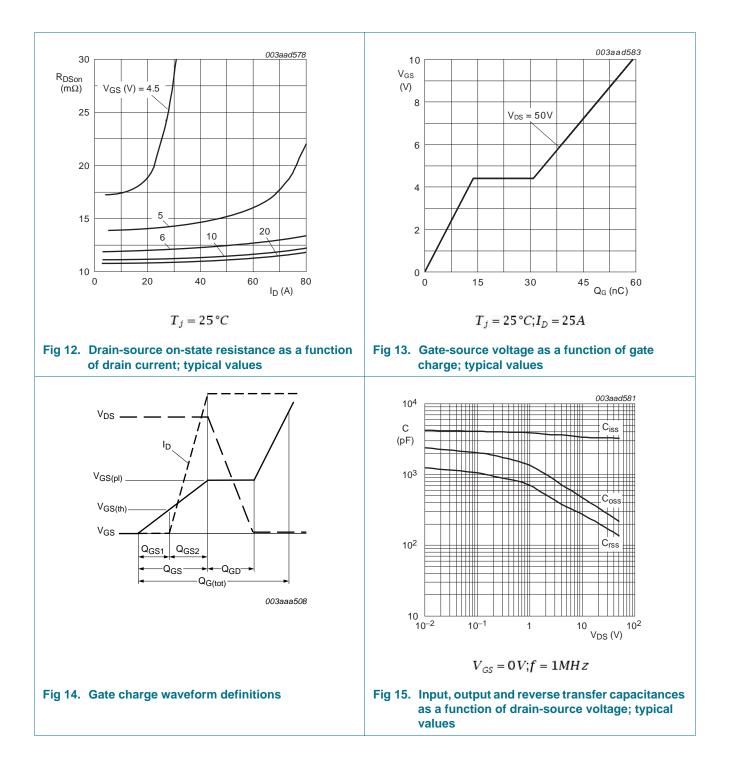
## **PSMN013-100ES**

#### N-channel 100V 13.9mΩ standard level MOSFET in I2PAK.



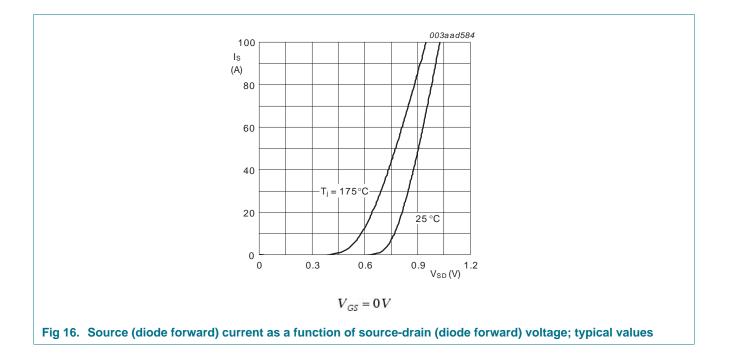
## **PSMN013-100ES**

#### N-channel 100V 13.9mΩ standard level MOSFET in I2PAK.



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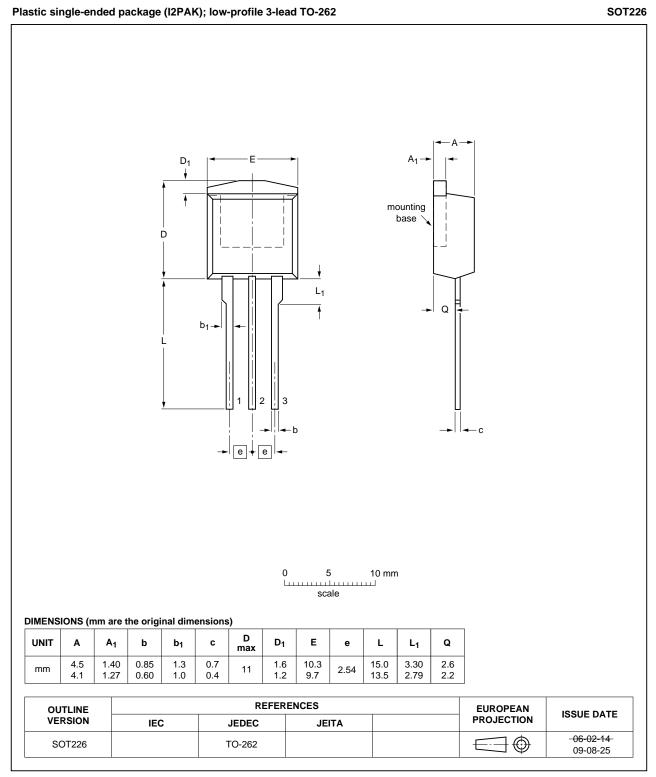
#### N-channel 100V 13.9m $\Omega$ standard level MOSFET in I2PAK.



## **PSMN013-100ES**

N-channel 100V 13.9mΩ standard level MOSFET in I2PAK.

### 7. Package outline



#### Fig 17. Package outline SOT226 (I2PAK)

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N-channel 100V 13.9m $\Omega$  standard level MOSFET in I2PAK.

## 8. Revision history

Table 7. Revision h	istory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN013-100ES v.3	20110929	Product data sheet	-	PSMN013-100ES v.2
Modifications:	<ul> <li>Status change</li> </ul>	ed from objective to product.		
	<ul> <li>Various chang</li> </ul>	ges to content.		
PSMN013-100ES v.2	20100219	Objective data sheet	-	PSMN013-100ES v.1

### 9. Legal information

#### 9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

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